REMARKS

Claims 1-7 are pending. Claims 1-7 are rejected. Claims 1 and 4 have been amended. No new matter has been added.

Drawings

The drawings are objected to in the outstanding Office Action. Formal drawings are transmitted herewith. Accordingly, the Applicants respectfully request the withdrawal of the outstanding objections to the drawings.

103 Rejection

Claims 1-7 are rejected under 35 U.S.C. § 103(a) as being unpatentable over Turnquist et al. The Applicants have reviewed the cited reference and respectfully submit that the present invention as is set forth in Claims 1-7 is not either anticipated or rendered obvious by Turnquist et al.

The Examiner is respectfully directed to independent Claim 1, which recites that embodiments of the present invention are directed to an apparatus for testing and integrated circuit comprising:

...a data source coupled to the integrated circuit to provide test signals to the integrated circuit; a plurality of relays selectively coupling the integrated circuit to the apparatus wherein the integrated circuit is tested; a plurality of fan out elements coupled to receive data pulses from the plurality of relays and to distribute the data pulses to a plurality of latches; and a strobe element associated with each of the plurality of latches for enabling each of the plurality of latches to transfer the data pulses from an input port to an output port of each of the plurality of latches.

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Independent Claim 4 recites limitations similar to those found in Claim 1. Claims 2 and 3 depend from Claim 1 and recite further limitations of the claimed invention. Claims 5-7 depend from Claim 4 and recite further limitations of the claimed invention.

Turnquist et al. does not anticipate or render obvious an apparatus for testing an integrated circuit comprising, "a plurality of fan out elements coupled to receive data pulses from the <u>plurality of</u> relays and to distribute the data pulses to a plurality of latches" as is recited in Claim 1. In addition, Turnquist et al. does not show or suggest "a plurality of relays selectively <u>coupling</u> the integrated circuit apparatus wherein the integrated circuit is tested" or "a strobe element associated with each of the plurality of latches for enabling each of the plurality of latches to transfer the data pulses from an input port to an output port of each of the plurality of latches" as is further recited in Claim 1.

It should be appreciated that Claim 1 requires that the components of the apparatus for testing an integrated circuit be arranged and function in a specifically defined manner. As such, a reference must show or suggest the specifically defined arrangement and function of the components in order to teach the claimed limitations. Importantly, absent a teaching or suggestion of the specifically recited arrangement and function of the components of the apparatus for testing an integrated circuit, a mere disclosure by Turnquist et al. of some of the components of the recited device is insufficient to teach the claimed invention.

Turnquist et al. merely shows an event based semiconductor test system. Nowhere in Turnquist et al. is there shown fan out elements that receive data pulses from an integrated circuit being tested (via a plurality of relays) and that are connected to distribute data pulses

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to a plurality of latches (that are enabled by a strobe) as is recited in Claims 1 and 4.

Consequently, Turnquist et al. does not anticipate or render obvious the embodiments of the Applicants' invention as are set forth in independent Claims 1 and 4.

In the outstanding Office Action the Examiner failed to indicate how the limitations of the Claims read on the information provided on pages 3 and 4 that is alleged by the Examiner to teach the claimed invention. As such, the Examiners position as to how the limitations of the Claims read on the cited Turnquist et al. disclosures is unclear. The Examiners statement of the grounds of rejection should be expressed in a manner that is clearly developed so as to be informative to the Applicants (see MPEP 706.7 and 707.07(d)). The Applicant respectfully requests that the Examiner provide a clear explanation of how each of the limitations of the Claims read on subject matter identified in Turnquist et al. as teaching the respective limitation in the next Office Action.

Therefore, Applicants respectfully submit that Turnquist et al. does not anticipate or render obvious the present claimed invention as is recited in Claims 1 and 4, and as such, Claims 1 and 4 are in condition for allowance. Accordingly, Applicants also respectfully submit that Turnquist et al. does not anticipate or render obvious the present claimed invention as is recited in Claims 2 and 3 dependent on Claim 1, and Claims 5-7 dependent on Claim 4, and that Claims 2, 3 and 5-7 overcome the Examiners basis for rejection under 35 U.S.C. 103 as being dependent on an allowable base claim.

Conclusion

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In light of the above-listed remarks, Applicants respectfully request allowance of the remaining Claims.

The Examiner is urged to contact Applicants' undersigned representative if the Examiner believes such action would expedite resolution of the present Application.

Respectfully submitted,

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Dated: $\frac{5}{20}$, 2004

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